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- Members of the Texas Instruments
   Widebus™ Family
- EPIC™ (Enhanced-Performance Implanted CMOS) Process
- Inputs Are TTL-Voltage Compatible
- Distributed V<sub>CC</sub> and GND Pins Minimize High-Speed Switching Noise
- Flow-Through Architecture Optimizes PCB Layout
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- ESD Protection Exceeds 2000 V Per
   MIL-STD-883, Method 3015; Exceeds 200 V
   Using Machine Model (C = 200 pF, R = 0)
- Package Options Include Plastic Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Thin Very Small-Outline (DGV) Packages and 380-mil Fine-Pitch Ceramic Flat (WD) Package Using 25-mil Center-to-Center Spacings

#### description

The 'AHCT16374 devices are 16-bit edge-triggered D-type flip-flops with 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. They are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

SN54AHCT16374 . . . WD PACKAGE SN74AHCT16374 . . . DGG, DGV, OR DL PACKAGE (TOP VIEW)



These devices can be used as two 8-bit flip-flops or one 16-bit flip-flop. On the positive transition of the clock (CLK) input, the Q outputs of the flip-flop take on the logic levels at the data (D) inputs.

A buffered output-enable (OE) input can be used to place the eight outputs in either a normal logic state (high or low logic levels) or the high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and the increased drive provide the capability to drive bus lines without need for interface or pullup components.

To ensure the high-impedance state during power up or power down,  $\overline{OE}$  should be tied to  $V_{CC}$  through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

OE does not affect internal operations of the flip-flop. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

The SN54AHCT16374 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74AHCT16374 is characterized for operation from –40°C to 85°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

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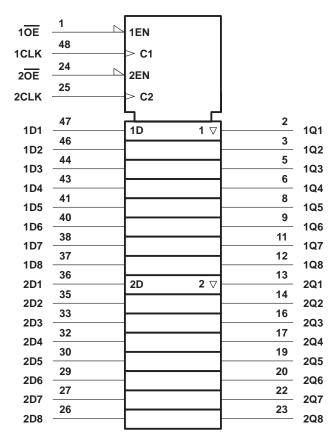


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## FUNCTION TABLE (each 8-bit flip-flop)

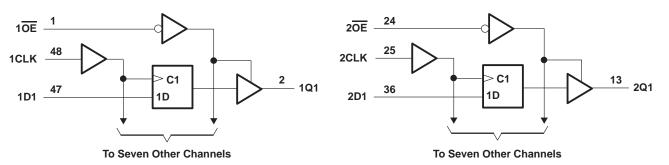
	INPUTS	OUTPUT	
OE	CLK	D	Q
L	1	Н	Н
L	$\uparrow$	L	L
L	H or L	Χ	Q <sub>0</sub>
Н	Χ	Χ	Z

### logic symbol†



<sup>&</sup>lt;sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

### logic diagram (positive logic)





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### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V <sub>CC</sub>		0.5 V	′ to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)		0.5 V	′ to 7 V
Output voltage range, VO (see Note 1)			
Input clamp current, $I_{IK}$ ( $V_I < 0$ )			
Output clamp current, $I_{OK}$ ( $V_O < 0$ or $V_O > V_{CC}$			
Continuous output current, $I_O$ ( $V_O = 0$ to $V_{CC}$ )			
Continuous current through each V <sub>CC</sub> or GND			
Package thermal impedance, $\theta_{\text{JA}}$ (see Note 2):			
5 1 / JA ( /	DGV package		
	DL package		
Storage temperature range, T <sub>stg</sub>			

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51.

### recommended operating conditions (see Note 3)

		SN54AHCT16374		SN74AHC	T16374	UNIT
		MIN	MAX	MIN	MAX	UNIT
Vcc	Supply voltage	4.5	5.5	4.5	5.5	V
VIH	High-level input voltage	2	2	2		V
VIL	Low-level input voltage		8.0		0.8	V
VI	Input voltage	0 <	5.5	0	5.5	V
Vo	Output voltage	0	Vcc	0	Vcc	V
loh	High-level output current	3	-8		-8	mA
loL	Low-level output current	30%	8		8	mA
Δt/Δν	Input transition rise or fall rate	Q	20		20	ns/V
TA	Operating free-air temperature	-55	125	-40	85	°C

NOTE 3: All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



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## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEST CONDITIONS	, , , , , , , , , , , , , , , , , , ,	T <sub>A</sub> = 25°C			SN54AHCT16374		SN74AHCT16374		UNIT
PARAMETER	TEST CONDITIONS	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
Vон	I <sub>OH</sub> = -50 μA	4.5 V	4.4	4.5		4.4		4.4		V
	$I_{OH} = -8 \text{ mA}$	4.5 V	3.94			3.8		3.8		V
Voi	I <sub>OL</sub> = 50 μA	4.5 V			0.1		0.1		0.1	V
VOL	$I_{OL} = 8 \text{ mA}$	4.5 V			0.36		0.44		0.44	V
lį	$V_I = V_{CC}$ or GND	0 V to 5.5 V			±0.1		±1*		±1	μΑ
loz	$V_O = V_{CC}$ or GND, $V_I = V_{IH}$ or $V_{IL}$	5.5 V			±0.25	457	±2.5		±2.5	μΑ
Icc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			4	20	40		40	μΑ
∆l <sub>CC</sub> †	One input at 3.4 V, Other inputs at V <sub>CC</sub> or GND	5.5 V			1.35	d	1.5		1.5	mA
Ci	V <sub>I</sub> = V <sub>CC</sub> or GND	5 V		2.5	10				10	pF
Co	$V_O = V_{CC}$ or GND	5 V		3.5					·	pF

 $<sup>^{\</sup>star}$  On products compliant to MIL-PRF-38535, this parameter is not production tested at  $V_{CC}$  = 0 V.

## timing requirements over recommended operating free-air temperature range, $V_{CC}$ = 5 V $\pm$ 0.5 V (unless otherwise noted) (see Figure 1)

		T <sub>A</sub> = 25°C SN54AHCT16		SN74AHCT16374	UNIT
		MIN MAX	MIN MAX	MIN MAX	UNIT
t <sub>W</sub>	Pulse duration, CLK high or low	6.5	6.5	6.5	ns
t <sub>su</sub>	Setup time, data before CLK↑	2.5	2.5	2.5	ns
th	Hold time, data after CLK↑	2.5	2.5	2.5	ns



<sup>†</sup> This is the increase in supply current for each input at one of the specified TTL voltage levels rather than 0 V or VCC.

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# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 5 V $\pm$ 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	LOAD	T,	<sub>Δ</sub> = 25°C	;	SN54AHC	T16374	SN74AHC	T16374	UNIT												
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII												
			C <sub>L</sub> = 15 pF	90*	140*		80*		110		MHz												
fmax			C <sub>L</sub> = 50 pF	85	130		75		75		IVITIZ												
t <sub>PLH</sub>	CLK	Q	C <sub>I</sub> = 15 pF		6.5*	9.4*	1*	10.5*	1	10.5	ns												
tPHL	CLK	Q .	CL = 15 pr		6.5*	9.4*	1*	10.5*	1	10.5	115												
<sup>t</sup> PZH	ŌĒ	Q	C 15 pE		6.5*	9.5*	1*	10.5*	1	10.5	ns												
t <sub>PZL</sub>	OE	Q	Q	Q	ų ų	ų ų	l Q	Q	Q	Q	Q	Q	Q	Q	C <sub>L</sub> = 15 pF		6.5*	9.5*	1*	10.5*	1	10.5	115
t <sub>PHZ</sub>	ŌĒ	Q	C <sub>L</sub> = 15 pF		6.2*	10.2*	1*2	11*	1	11	ns												
t <sub>PLZ</sub>	OE	L Q	Q	Q	GL = 13 pr		6.2*	10.2*	1/*	11*	1	11	115										
<sup>t</sup> PLH	CLK	Q	C <sub>I</sub> = 50 pF		7.3	10.4	201	11.5	1	11.5	ns												
t <sub>PHL</sub>	OLK	ų ,	CL = 30 pr		7.1	10.4	O <sub>6</sub> / <sub>1</sub>	11.5	1	11.5	115												
<sup>t</sup> PZH	ŌE	Q	C <sub>I</sub> = 50 pF		6.2	10.5	1	11.5	1	11.5	ns												
tPZL	OE	ų ,	CL = 30 pr		5.1	10.5	1	11.5	1	11.5	115												
<sup>t</sup> PHZ	ŌĒ	Q	C <sub>1</sub> = 50 pF		7.1	11.2	1	12	1	12	ns												
<sup>t</sup> PLZ	UE	<u> </u>	OL = 30 pi		7.9	11.2	1	12	1	12	113												
tsk(o)			C <sub>L</sub> = 50 pF			1**				1	ns												

### noise characteristics, $V_{CC} = 5 \text{ V}$ , $C_L = 50 \text{ pF}$ , $T_A = 25^{\circ}\text{C}$ (see Note 4)

	PARAMETER			SN74AHCT16374		
	PARAMETER	MIN	TYP	MAX	UNIT	
V <sub>OL(P)</sub>	Quiet output, maximum dynamic V <sub>OL</sub>		0.36	0.8	V	
V <sub>OL(V)</sub>	Quiet output, minimum dynamic V <sub>OL</sub>		-0.1	-0.8	V	
VOH(V)	Quiet output, minimum dynamic V <sub>OH</sub>		4.7		V	
V <sub>IH(D)</sub>	High-level dynamic input voltage	2			V	
V <sub>IL(D)</sub>	Low-level dynamic input voltage			0.8	V	

NOTE 4: Characteristics are for surface-mount packages only.

### operating characteristics, $V_{CC}$ = 5 V, $T_A$ = 25°C

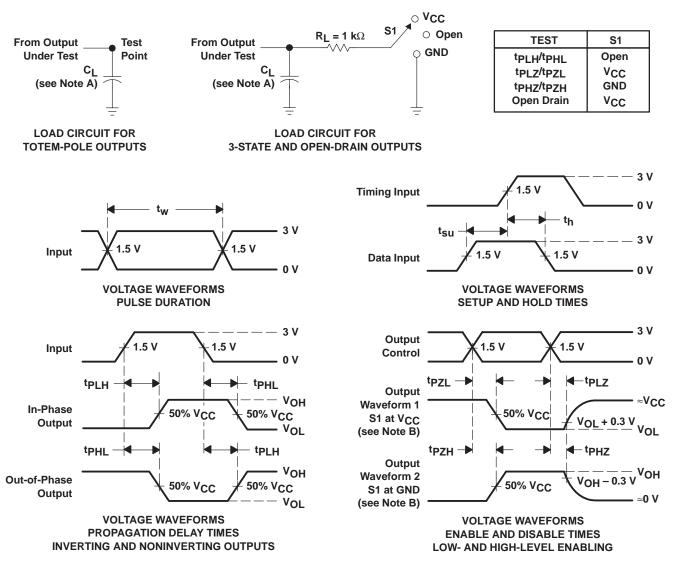
PARAMETER	TEST CONDITIONS	TYP	UNIT
C <sub>pd</sub> Power dissipation capacitance	No load, f = 1 MHz	27	pF



<sup>\*</sup> On products compliant to MIL-PRF-38535, this parameter is not production tested. 
\*\* On products compliant to MIL-PRF-38535, this parameter does not apply.

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#### PARAMETER MEASUREMENT INFORMATION



NOTES: A. C<sub>I</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_Q = 50 \Omega$ ,  $t_f \leq 3$  ns,  $t_f \leq 3$  ns.
- $\label{eq:defD} \textbf{D.} \quad \text{The outputs are measured one at a time with one input transition per measurement.}$

Figure 1. Load Circuit and Voltage Waveforms



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